

COMPLIANT

STP2N95K5-VB Datasheet

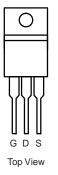
N-Channel 900V (D-S) Super Junction Power MOSFET

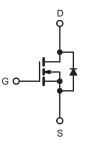
PRODUCT SUMMARY					
V _{DS} (V)	900				
R _{DS(on)} (Ω)	V _{GS} = 10 V 1.3				
Q _g (Max.) (nC)	200				
Q _{gs} (nC)	24				
Q _{gd} (nC)	110				
Configuration	Single				

FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Isolated Central Mounting Hole
- · Fast Switching
- · Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC







N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T _C	= 25 °C, unl	ess otherwis	se noted)			
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V _{DS}	900	V	
Gate-Source Voltage			V _{GS}	± 20	v	
Continuous Drain Current	V _{GS} at 10 V	T _C = 25 °C	I_	5		
Continuous Drain Current	VGS at TO V	T _C = 100 °C	I _D	3.9	A	
Pulsed Drain Current ^a			I _{DM}	21		
Linear Derating Factor				1.5	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	770	mJ	
Repetitive Avalanche Current ^a			I _{AR}	7.8	A	
Repetitive Avalanche Energy ^a			E _{AR}	19	mJ	
Maximum Power Dissipation $T_{C} = 25 \text{ °C}$			PD	190	W	
Peak Diode Recovery dV/dt ^c			dV/dt	2.0	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 150	- °C	
Soldering Recommendations (Peak Temperature) for 10 s		-	300 ^d			
Mounting Torque	6-32 or M3 screw			10	lbf ∙ in	
				1.1	N · m	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. $V_{DD} = 50 \text{ V}$, starting $T_J = 25 \text{ °C}$, L = 23 mH, $R_g = 25 \Omega$, $I_{AS} = 7.8 \text{ A}$ (see fig. 12). c. $I_{SD} \leq 7.8 \text{ A}$, dI/dt $\leq 140 \text{ A/}\mu\text{s}$, $V_{DD} \leq 600 \text{ V}$, $T_J \leq 150 \text{ °C}$.

d. 1.6 mm from case.

* Pb containing terminations are not RoHS compliant, exemptions may apply

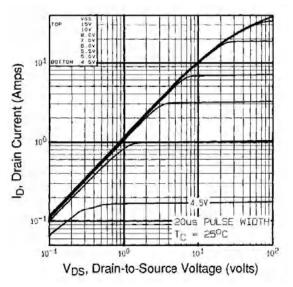
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THERMAL RESISTANCE RATI	NGS							
PARAMETER	SYMBOL	TYP.		MAX.			UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-		40				
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.24		-			°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	- 0.65						
	nlago othornui	aa natad)						
SPECIFICATIONS (T _J = 25 °C, u PARAMETER	SYMBOL	1	T CONDIT		MIN.	TYP.	MAX.	UNIT
Static	OTMEDE	120			IVIIIA.		WAA.	UNIT
Drain-Source Breakdown Voltage	V _{DS}	Vcs	= 0 V, I _D =	250 µA	900	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$		e to 25 °C,	•	-	0.98	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}		= V _{GS} , I _D =		2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}		$V_{GS} = \pm 20$		-	-	± 100	nA
	'655		= 800 V, V _G		_		100	10.0
Zero Gate Voltage Drain Current	I _{DSS}	-		/, T _J = 125 °C	_	_	500	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V			-	1.3	-	Ω
Forward Transconductance	g _{fs}		= 100 V, I _D :		5.6	-	-	S
Dynamic	010					I		
Input Capacitance	C _{iss}		V = 0.V	1	-	3100	-	
Output Capacitance	C _{oss}	$V_{GS} = 0 V,$ $V_{DS} = 25 V,$			-	800	-	pF
Reverse Transfer Capacitance	C _{rss}	f = 1	f = 1.0 MHz, see fig. 5		-	490	-	
Total Gate Charge	Qg				-	-	200	
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V		A, $V_{DS} = 400 V$,	-	-	24	nC
Gate-Drain Charge	Q _{gd}	_	see fig. 6 and 13 ^b		-	-	110	1
Turn-On Delay Time	t _{d(on)}				-	19	-	
Rise Time	t _r	V _{DD} = 400 V, I _D = 3.8 A,		-	38	-	1	
Turn-Off Delay Time	t _{d(off)}	$V_{DD} = 400 \text{ V}, \text{ I}_{D} = 3.8 \text{ A}, - \\ \text{R}_{g} = 6.2 \Omega, \text{ R}_{D} = 52 \Omega \\ \text{see fig. 10^{b}} - $		120	-	ns		
Fall Time	t _f		see fig. 10 ^b		-	39	-	1
Internal Drain Inductance	L _D	Between lead 6 mm (0.25") 1	,		-	5.0	-	
Internal Source Inductance	Ls	package and center of die contact		-	13	-	nH	
Drain-Source Body Diode Characteristic	s	<u> </u>			L			I
Continuous Source-Drain Diode Current	I _S	MOSFET symbol		5.0				
Pulsed Diode Forward Current ^a	I _{SM}	integral reverse p - n junction diode			-	-	21	A
Body Diode Voltage	V _{SD}	$T_{J} = 25 \ ^{\circ}C, I_{S} = 3.8 \ A, V_{GS} = 0 \ V^{b}$		-	-	1.8	V	
Body Diode Reverse Recovery Time	t _{rr}	$ T_{J} = 25 \text{ °C}, I_{F} = 3.8 \text{ A}, \\ dl/dt = 100 \text{ A}/\mu\text{s}^{b} $		-	650	980	ns	
Body Diode Reverse Recovery Charge	Q _{rr}			-	3.8	5.7	μC	
Forward Turn-On Time	t _{on}	Intrinsic tu	rn-on time	is negligible (turn	-on is do	ninated h	v Le and	L _D)

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. Pulse width ≤ 300 µs; duty cycle ≤ 2 %.





TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



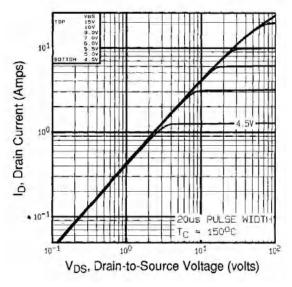


Fig. 2 - Typical Output Characteristics, $T_C = 150$ °C

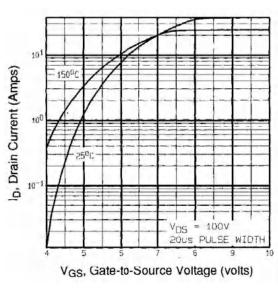
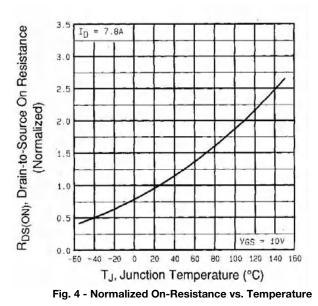


Fig. 3 - Typical Transfer Characteristics





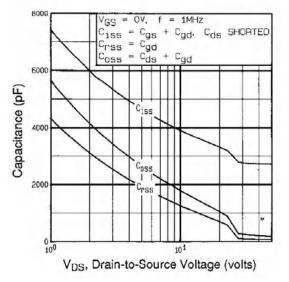


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

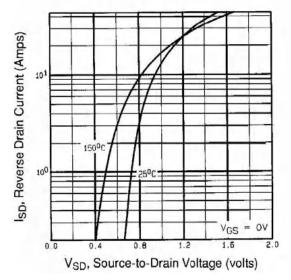


Fig. 7 - Typical Source-Drain Diode Forward Voltage

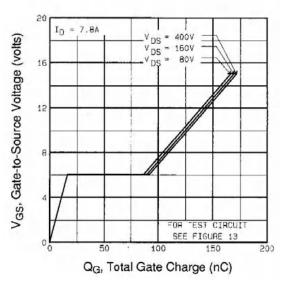
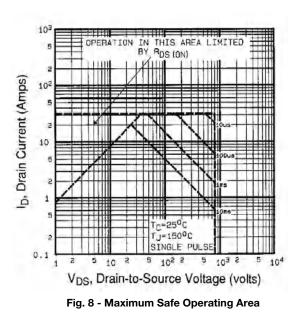


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage





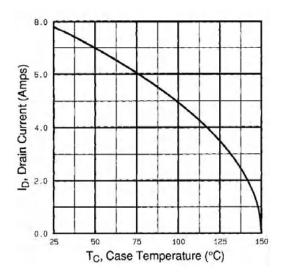


Fig. 9 - Maximum Drain Current vs. Case Temperature

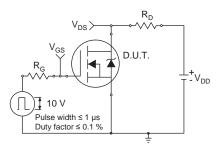


Fig. 10a - Switching Time Test Circuit

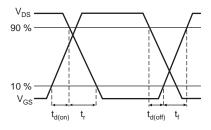


Fig. 10b - Switching Time Waveforms

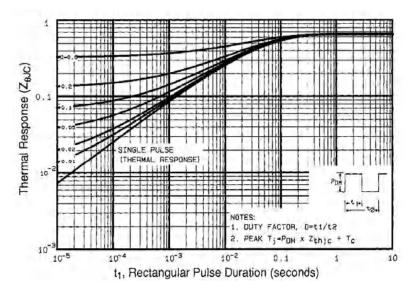


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



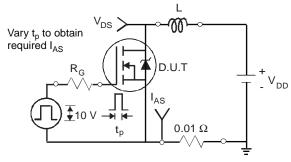


Fig. 12a - Unclamped Inductive Test Circuit

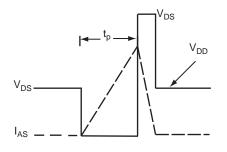


Fig. 12b - Unclamped Inductive Waveforms

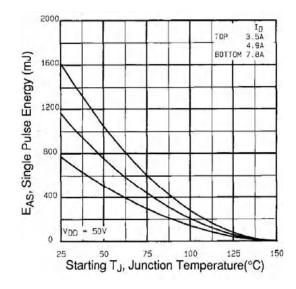


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

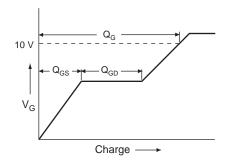


Fig. 13a - Basic Gate Charge Waveform

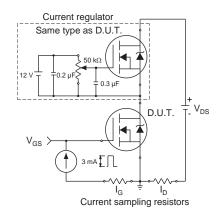
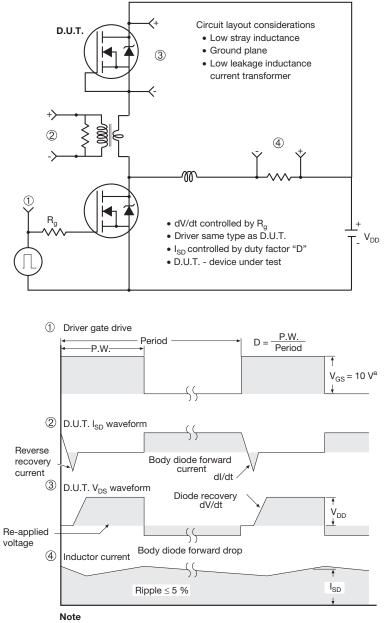


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit

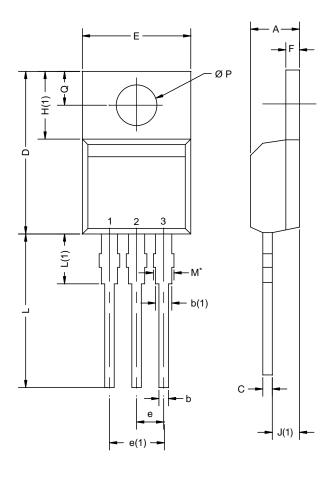


a. $V_{GS} = 5$ V for logic level devices

Fig. 14 - For N-Channel



TO-220AB



	MILLIN	IETERS	INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
А	4.25	4.65	0.167	0.183
b	0.69	1.01	0.027	0.040
b(1)	1.20	1.73	0.047	0.068
С	0.36	0.61	0.014	0.024
D	14.85	15.49	0.585	0.610
E	10.04	10.51	0.395	0.414
е	2.41	2.67	0.095	0.105
e(1)	4.88	5.28	0.192	0.208
F	1.14	1.40	0.045	0.055
H(1)	6.09	6.48	0.240	0.255
J(1)	2.41	2.92	0.095	0.115
L	13.35	14.02	0.526	0.552
L(1)	3.32	3.82	0.131	0.150
ØР	3.54	3.94	0.139	0.155
Q	2.60	3.00	0.102	0.118
ECN: X12- DWG: 547	0208-Rev. N, 1	08-Oct-12		

Notes

* M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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